PAST TTTC EVENTS

13th IEEE European Test Symposium (ETS 08)
25-29 May 2008
Verbania, Italy
http://www.cad.polito.it/~ets08

The IEEE European Test Symposium is Europe’s premier forum dedicated to presenting and discussing scientific results, emerging ideas, practical applications, hot topics, and new trends in electronic-based circuits and systems testing. This annual event has undergone healthy growth and continued quality improvement since it was first organized in 1996.

IEEE International Mixed-Signals, Sensors, and Systems Test Workshop (IMS3TW 08)
18-20 June 2008
Vancouver, Canada
http://www.lirmm.fr/~w3mic/IMS3TW08

The IEEE Mixed-Signal Test Workshop (IMSTW) was inaugurated in 1995 as a forum focused on test and DFT issues related to systems encompassing digital and analog electrical signals. In view of accelerated developments in heterogeneous design and production, in 2008 the workshop increased its scope to include new topics focusing on challenges and solutions associated with test, DFT, reliability, and manufacturability of emerging and envisaged heterogeneous systems. Renamed to include sensors and systems, the new IMS3TW aims to bring research and technical expertise for the next generation of devices, circuits, and systems. IMS3TW will continue to address the traditional technology spectrum of IMSTW—in particular, all aspects of analog, mixed-signal, and RF testing—but with increased attention on all aspects of design complexity. Guaranteeing design robustness for the next generation of nanoelectronic devices may require exploiting self-monitoring functionality so that the circuit or system can adapt to varying circuit parameters or functional demands. Built-in sensors can play a crucial role to facilitate device adaptability.

UPCOMING TTTC EVENTS

1st IEEE International Workshop on Design and Test of Nano Devices, Circuits and Systems (NDCS 08)
29-30 September 2008
Cambridge, Massachusetts
http://ndcs08.arces.unibo.it/cfp.htm

Over the past few years, emerging technologies have asserted a prominent role for future innovation in the electronics and computer industry at the nanometer scale. The potential of these breakthrough technologies is wide-ranging and is expected to eventually supersede at least some of the limitations of CMOS predicted at the end of the International Technology Roadmap for Semiconductors. Novel computational paradigms and new manufacturing and fabrication processes are being introduced to the technical community. Nanodevice, circuit, and system implementations for diverse applications are currently being investigated to implement the next generation of electronics and digital computers. This workshop provides an open forum for presentations in this field. All aspects of design, manufacturing, test, and reliability of innovative nanocircuits and systems are of interest.

23rd IEEE International Symposium on Defect and Fault Tolerance in VLSI Systems (DFT 08)
1-3 October 2008
Cambridge, Massachusetts
http://www.dfts.org

DFT provides an open forum for presentations on defect and fault tolerance in VLSI systems, including emerging technologies. One of the unique features of this annual symposium is that it combines new academic research with state-of-the-art industrial data—necessary ingredients for significant advances in this field. All aspects of design, manufacturing, test, reliability, and availability that are affected by defects during manufacturing and by faults during system operation are of interest.
17th Asian Test Symposium (ATS 08)
24-27 November 2008
Sapporo, Japan
http://ats08.info.hiroshima-cu.ac.jp

ATS provides an international forum for engineers and researchers from throughout the world, but especially Asia, to present and discuss various aspects of device, board, and system testing with design, manufacturing, and field considerations in mind.

Calls for Papers
9th IEEE Workshop on RTL and High Level Testing (WRTLTT 08)
27-28 November 2008
Sapporo, Japan
http://aries3a.cse.kyutech.ac.jp/wrtlt08

This annual workshop is held in conjunction with the 17th Asian Test Symposium. The purpose of this workshop is to bring together researchers and practitioners on large-scale integration (LSI) testing from all over the world to exchange ideas and experiences on RTL and high-level testing.

Submissions deadline: 25 July 2008
For further information, please e-mail wrtlt08@aries3a.cse.kyutech.ac.jp.

NEWSLETTER
EDITOR’S INVITATION
I would appreciate input and suggestions about the newsletter from the test community. Please forward your ideas, contributions, and information on awards, conferences, and workshops to Bruce C. Kim, Dept. of Electrical and Computer Engineering, Univ. of Alabama, 317 Houser Hall, Tuscaloosa, AL 35487-0286; bruce.kim@ieee.org.

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